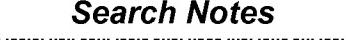


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/761,386	FUNAKOSHI ET AL.	
	Examiner	Art Unit	
	VAN T. PHAM	2627	

Search Notes



Application/Control No.

10/761,386

Examiner

VAN T. PHAM

**Applicant(s)/Patent under
Reexamination**

FUNAKOSHI ET AL.

Art Unit

2627

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner